

# Polynomial Identity Testing and Circuit Lower Bounds

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based on papers by

Nisan & Wigderson, 1994

Kabanets & Impagliazzo, 2003

# Randomised algorithms

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- For some problems (polynomial identity testing) we know an efficient randomised algorithm, but not a deterministic one.
- However nobody proved  $P \subsetneq BPP$  yet.  
It is possible that  $P = BPP$ .
- There is a connection between *hardness* and *randomness*:  
if we have a hard function, we can use it to *derandomize* BPP.
- Until recently, it was not known whether the converse holds.  
Kabanets & Impagliazzo showed that it does.
- This is bad, since non-trivial circuit lower-bounds are a long-standing open problem.

# Pseudo-random generators

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$G : \{0,1\}^{\ell(n)} \rightarrow \{0,1\}^n$  is a *pseudo-random generator* iff for any circuit  $C$  of size  $n$ :

$$|P[C(r) = 1] - P[C(G(x)) = 1]| < \frac{1}{n},$$

where  $x, r$  are chosen uniformly.

Having a pseudo-random generator, we can *derandomize* BPP:

- instead of  $n$  random bits, plug a pseudo-random sequence (acceptance prob. changed only slightly)
- check all  $2^{\ell(n)}$  random seeds

## Hard functions

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$f_n : \{0,1\}^n \rightarrow \{0,1\}$  has *hardness*  $h$   
iff for any circuit  $C$  of size  $h$ :

$$\left| P[C(x) = f(x)] - \frac{1}{2} \right| < \frac{1}{2h'}$$

where  $x$  is chosen uniformly.

Hard functions can be used to build pseudo-random generators:

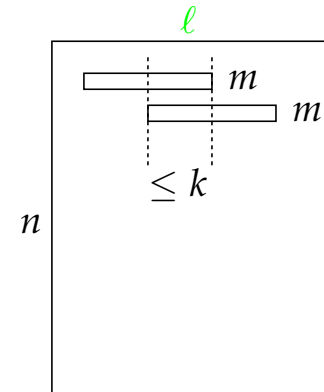
- take  $\ell(n)$  truly random bits
- evaluate  $f$  on  $n$  subsets of them
- if these subsets have small intersection, then the results are hardly correlated

# Nearly disjoint sets

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System of sets  $\{S_1, \dots, S_n\}$ , where  $S_i \subset \{1, \dots, \ell\}$  is a  $(k, m)$ -design if:

- $|S_i| = m$
- $|S_i \cap S_j| \leq k$



For every  $m \in \{\log n, \dots, n\}$ , there exists an  $n \times \ell$  matrix which is a  $(\log n, m)$ -design, where  $\ell = O(m^2)$ .

(If  $m = O(\log n)$ , then even  $\ell = O(m)$  is enough.)

Assume  $m$  is a prime power. Take  $S_q = \{\langle x, q(x) \rangle \mid x \in GF(m)\}$ , where  $q$  has degree at most  $\log n$ . Can be computed in log-space.

# Nisan & Wigderson, 1994

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Let  $f$  have *hardness*  $\geq n^2$  and  $S$  be a  $(\log n, m)$ -*design*. Then  $G : \{0,1\}^\ell \rightarrow \{0,1\}^n$  given by  $G(x) = f_S(x)$  is a pseudo-random generator.

**1.** Assume a circuit  $C$  distinguishes random  $r$  and  $y = G(x)$  w.p.  $> \frac{1}{n}$ .

Let  $p_i = P[C(z) = 1]$ , where  $z = y_1 \dots y_i r_{i+1} \dots r_n$ .

There must be  $i$  such that  $p_{i-1} - p_i > \frac{1}{n^2}$ .

**2.** Build a circuit  $D$  that predicts  $y_i$  from  $y_1 \dots y_{i-1}$  w.p.  $\geq \frac{1}{2} + \frac{1}{n^2}$

$D$  evaluates  $C(y_1 \dots y_{i-1}, r_i \dots r_n)$  and returns  $r_i$  iff  $C = 1$ .

3. Assume w.l.o.g.  $S_i = \{1, \dots, m\}$ , then  $y_i = f(x_1 \dots x_m)$ .  
Since  $y_i$  does not depend on other bits, there exists some *assignment of  $x_{m+1} \dots x_\ell$*  preserving the prediction prob.
4. After *fixing*, every  $y_1 \dots y_{i-1}$  depends only on  $\log n$  variables, hence can be computed from  $x$  as a CNF of size  $O(n)$ .
5. Plug computed  $y_1 \dots y_{i-1}$  into  $D$  and obtain a circuit predicting  $y_i$  from  $x$  w.p.  $\geq \frac{1}{2} + \frac{1}{n^2}$ .  
*This contradicts that  $f$  has hardness  $\geq n^2$ .*

# Hardness-randomness tradeoff

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If there exists a function computable in  $E = \text{DTIME}(2^{O(n)})$  that cannot be **approximated** by

1. polynomial-size circuits, then  $\text{BPP} \subset \bigcap_{\varepsilon > 0} \text{DTIME}(2^{n^\varepsilon})$ .
2. circuits of size  $2^{n^\varepsilon}$  for some  $\varepsilon > 0$ , then  $\text{BPP} \subset \text{DTIME}(2^{(\log n)^c})$  for some constant  $c$ .
3. circuits of size  $2^{\varepsilon n}$  for some  $\varepsilon > 0$ , then  $\text{BPP} = \text{P}$ .  
(We need to use  $(\log n, m)$ -design with  $\ell = O(m)$ .)



# Impagliazzo & Wigderson, 1997

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If some function in  $E$  has **circuit complexity**  $2^{\Omega(n)}$ , then  $BPP = P$ .

- Similar claim as **NW.3**, but assuming hardness in the *worst-case*.  
NW needed hardness on the *average*.
- Convert mildly hard function  $f$  to almost unpredictable function.  
Yao's XOR-Lemma:  $f(x_1) \oplus \dots \oplus f(x_k)$  is hard to predict,  
when  $x_i$  are independent.
- Use expanders to reduce the need for random bits.

## Is circuit lower bound needed?

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- $f$  is in BPP, if there is a randomised algorithm with error  $\leq \frac{1}{3}$  on *every input*
- $f$  is in promise-BPP, if there is a randomised algorithm with error  $\leq \frac{1}{3}$  on *some subset of inputs*, and we do not care the acceptance prob. on other inputs

### [Impagliazzo & Kabanets & Wigderson, 2002]

Promise-BPP = P implies NEXP  $\not\subseteq$  P/poly (circuit lower bound!).

### [Kabanets & Impagliazzo, 2003]

BPP = P implies super-polynomial *arithmetical* circuit lower bound for NEXP.

## Prerequisites of [KI03]

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- [Valiant, 1979] Perm is  $\#P$ -complete
  - $\text{Perm}(A) = \sum_{\sigma} \prod_{i=1}^n a_{i,\sigma(i)}$
  - $\#P$  is a class counting the number of solutions
- [Toda, 1991]  $\text{PH} \subset P^{\#P}$
- [Impagliazzo & Kabanets & Wigderson, 2002]  
 $\text{NEXP} \subset P/\text{poly} \implies \text{NEXP} = \text{MA}$

If  $\text{NEXP} \subset P/\text{poly}$ , then

1.  $\text{NEXP} = \text{MA} \subset \text{PH} \subset P^{\#P} \implies \text{Perm}$  is NEXP-hard
2.  $\text{Perm} \in \text{EXP} \subset \text{NEXP} \implies \text{Perm}$  is NEXP-complete

# Polynomial identity testing

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- is testing whether a given polynomial is identically zero
- is in **co-RP**: take a random point and evaluate the polynomial.  
If the field is big enough, we get nonzero with high prob.

Can test whether a given *arithmetical circuit*  $p_n$  computes Perm:

Input:  $p_n$  on  $n \times n$  variables, let  $p_i$  be its restriction to  $i \times i$  variables.

- test  $p_1(x) = x$  (by the method above)
- for  $i \in \{2, \dots, n\}$ , test  $p_i(X) = \sum_{j=1}^i x_{1,j} p_{i-1}(X_j)$ ,  
where  $X_j$  is the  $j$ -th minor

If all tests pass, then  $p_n = \text{Perm}$ .

# Circuit lower bounds from derandomization

- Suppose that *polynomial identity testing is in P*.
- If *Perm is computable by polynomial-size arithmetic circuits*, then  $\text{Perm} \in \text{NP}$ :
  1. guess the circuit for Perm
  2. verify its validity
  3. compute the result
- If  $\text{NEXP} \subset P/\text{poly}$ , then Perm is NEXP-complete.

Contradiction with nondeterministic time hierarchy theorem!

## Main result of KI03

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If  $BPP = P$ , or even  $BPP \subset NSUBEXP = \bigcap_{\epsilon > 0} NTIME(2^{n^\epsilon})$ ,  
then

- 1.** Perm does not have polynomial-size arithmetical circuits, **or**
- 2.**  $NEXP \not\subset P/poly$

# Summary

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- [NW94] Average circuit lower bounds imply derandomization
- [IW97] Worst-case circuit lower bounds imply derandomization
- [KI03] Derandomization implies circuit lower bounds